TOSHIBA Transistor Silicon PNP Epitaxial Type (PCT Process) Silicon NPN Epitaxial Type (PCT Process)

# HN1B01F

## Audio-Frequency General-Purpose Amplifier Applications

### Q1:

• High voltage and high current

 $: V_{CEO} = -50 \text{ V}, I_{C} = -150 \text{ mA (max)}$ 

• High  $h_{FE}$ :  $h_{FE} = 120 \sim 400$ 

• Excellent hfe linearity

:  $h_{FE}$  ( $I_{C} = -0.1 \text{ mA}$ ) /  $h_{FE}$  ( $I_{C} = -2 \text{ mA}$ ) = 0.95 (typ.)

#### **Q2**:

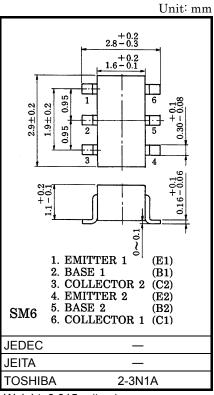
• High voltage and high current

 $: V_{CEO} = 50 \text{ V}, I_{C} = 150 \text{ mA (max)}$ 

• High hfE: hfE =  $120 \sim 400$ 

Excellent hFE linearity

:  $h_{FE}$  ( $I_{C} = 0.1 \text{ mA}$ ) /  $h_{FE}$  ( $I_{C} = 2 \text{ mA}$ ) = 0.95 (typ.)

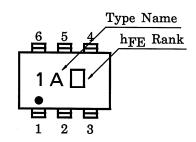


Weight: 0.015 g (typ.)

## Q1 Absolute Maximum Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	Unit
Collector-base voltage	$V_{CBO}$	-50	V
Collector-emitter voltage	V <sub>CEO</sub>	-50	V
Emitter-base voltage	V <sub>EBO</sub>	-5	V
Collector current	IC	-150	mA
Base current	ΙΒ	-50	mA

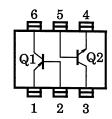
## Marking



## Q2 Absolute Maximum Ratings (Ta = 25°C)

## **Equivalent Circuit (Top View)**

Characteristic	Symbol	Rating	Unit
Collector-base voltage	$V_{CBO}$	60	V
Collector-emitter voltage	V <sub>CEO</sub>	50	V
Emitter-base voltage	V <sub>EBO</sub>	5	V
Collector current	IC	150	mA
Base current	ΙΒ	30	mA



## Q1, Q2 Common Absolute Maximum Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	Unit
Collector power dissipation	P <sub>C</sub> *	300	mW
Junction temperature	Tj	125	°C
Storage temperature range	T <sub>stg</sub>	-55~125	°C

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

## Q1 Electrical Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current	I <sub>CBO</sub>	_	$V_{CB} = -50 \text{ V}, I_{E} = 0$	_	_	-0.1	μA
Emitter cut-off current	I <sub>EBO</sub>	_	$V_{EB} = -5 \text{ V}, I_C = 0$	_	_	-0.1	μA
DC current gain	h <sub>FE (Note)</sub>	_	$V_{CE} = -6 \text{ V}, I_{C} = -2 \text{ mA}$	120	_	400	
Collector-emitter saturation voltage	V <sub>CE (sat)</sub>	_	I <sub>C</sub> = -100 mA, I <sub>B</sub> = -10 mA	-	-0.1	-0.3	V
Transition frequency	f <sub>T</sub>	_	V <sub>CE</sub> = −10 V, I <sub>C</sub> = −1 mA	_	120	_	MHz
Collector output capacitance	C <sub>ob</sub>	_	$V_{CB} = -10 \text{ V}, I_E = 0,$ f = 1 MHz		4	_	pF

## Q2 Electrical Characteristics (Ta = 25°C)

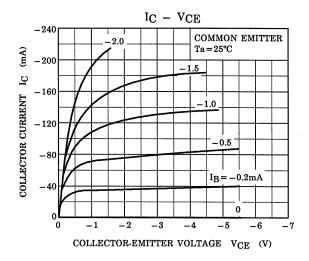
Characteristic	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current	I <sub>CBO</sub>	_	V <sub>CB</sub> = 60 V, I <sub>E</sub> = 0	-	-	0.1	μA
Emitter cut-off current	I <sub>EBO</sub>	_	$V_{EB} = 5 \text{ V}, I_{C} = 0$	_	_	0.1	μA
DC current gain	h <sub>FE (Note)</sub>	_	$V_{CE}$ = 6 V, $I_{C}$ = 2 mA	120	_	400	
Collector-emitter saturation voltage	V <sub>CE</sub> (sat)	_	I <sub>C</sub> = 100 mA, I <sub>B</sub> = 10 mA	-	0.1	0.25	٧
Transition frequency	f <sub>T</sub>	_	V <sub>CE</sub> = 10 V, I <sub>C</sub> = 1 mA	_	150	_	MHz
Collector output capacitance	C <sub>ob</sub>	_	$V_{CB} = 10 \text{ V}, I_{E} = 0,$ f = 1 MHz	-	2	_	pF

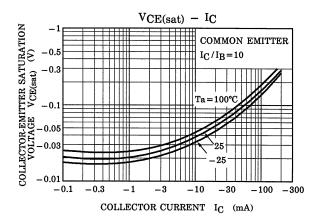
Note: hfe Classification Y (Y): 120~240, GR (G): 200~400

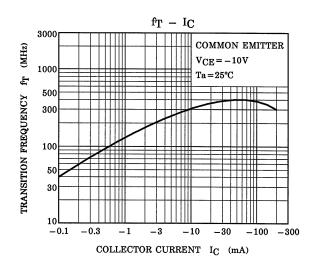
( ) Marking symbol

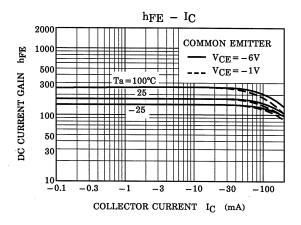
<sup>\*:</sup> Total rating

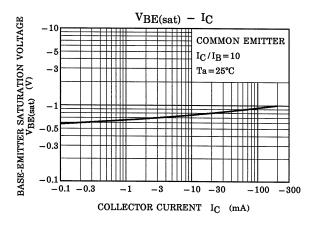
## Q1 (PNP Transistor)

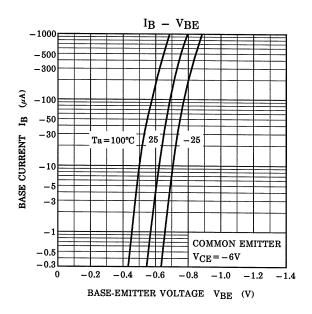




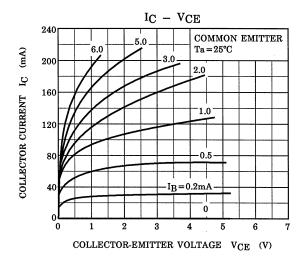


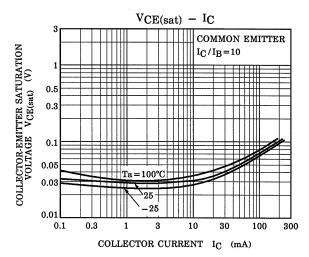


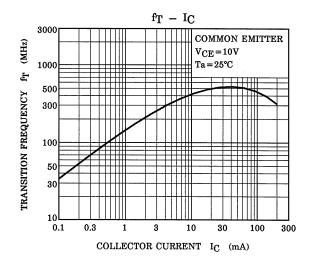


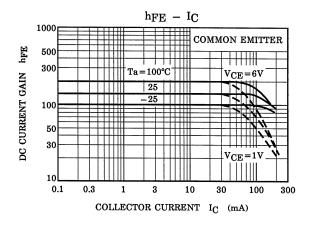


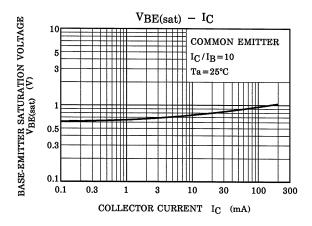
## **Q2 (NPN Transistor)**

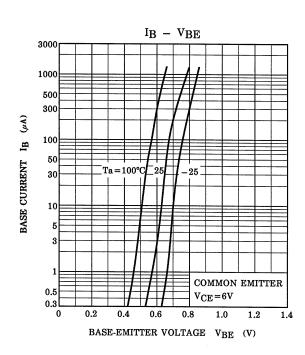




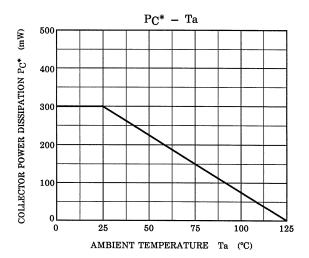








# (Q1, Q2 Common)



\* : Total Rating

5

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20070701-EN GENERAL

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